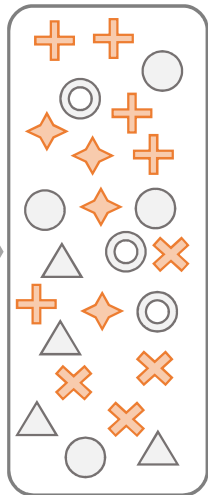


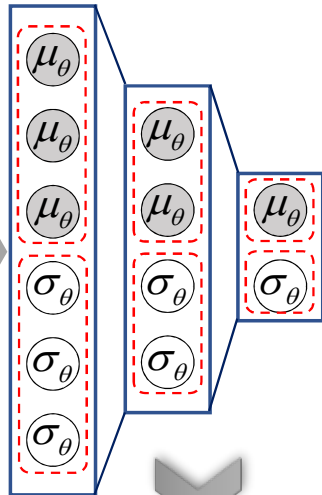
Device



Data



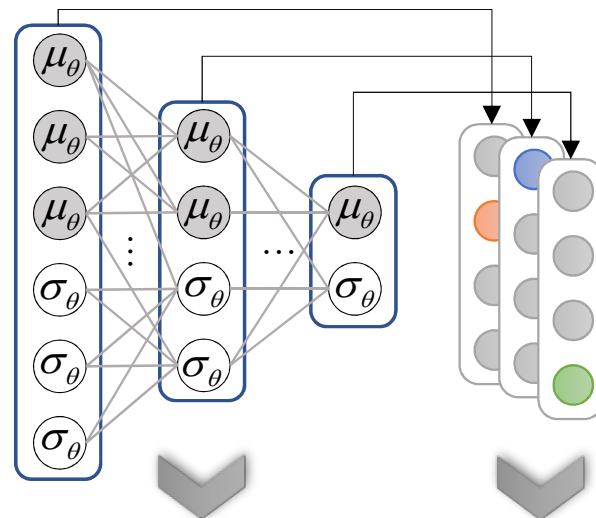
Backbone



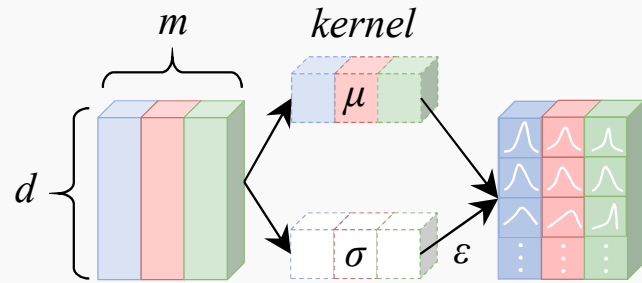
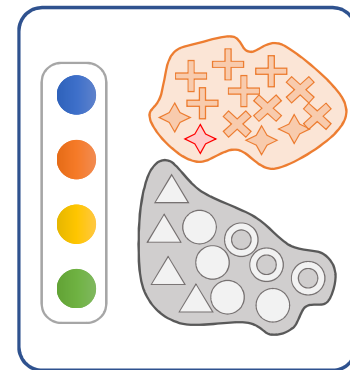
Features



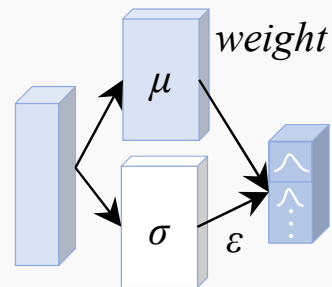
Hierarchical Classifiers



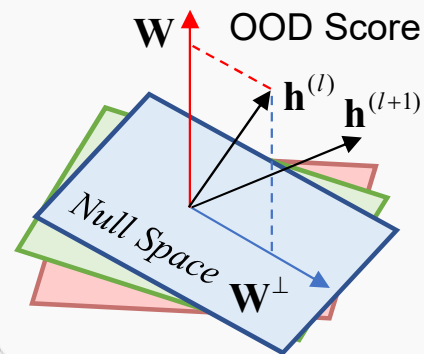
Fault Diagnosis with OOD Detection



Probabilistic Convolution



Probabilistic Linear



Uncertainty Estimation

